

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/084,968	ONO ET AL.	
Examiner	Art Unit	_
Christina Y. Leung	2633	

	SEARCHED			
Class	Subclass	Date	Examiner	
398	183	6/27/2005	Q	
398	186	6/27/2005	Cl	
398	188	6/27/2005	Q	
398	196	6/27/2005	Cl	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
398	186	6/27/2005	U	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST text search (see search history)	6/27/2005	ce
IEEE database search	6/27/2005	ce
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